

Notice of References Cited	Application/Control No. 10/666,304	Applicant(s)/Patent Under Reexamination VANBENSCHOTEN ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-4,931,343	06-1990	Becker et al.	428/95
	C	US-4,322,875	04-1982	Brown et al.	24/447
	D	US-3,849,174	11-1974	Ancker, Fred H.	427/365
	E	US-6,106,922	08-2000	Cejka et al.	428/120
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	G	US-6,669,887	12-2003	Hilston et al.	264/173.15
	H	US-6,896,759	05-2005	Fujisawa et al.	156/244.18
	I	US-5,260,015	11-1993	Kennedy et al.	264/167
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	K	US-5,669,120	09-1997	Wessels et al.	24/446
	L	US-5,800,760	09-1998	Takizawa et al.	264/167
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	E	US-3,773,882	11-1973	Schrenk	264/173.12
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	C	US-2002/0022108	02-2002	Krantz et al.	428/100
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